

Enhancement Mode N-Channel Power MOSFET

 $TO-220/NMOS/70V/\pm20V/3.0V/51A/6.1m\Omega$

Rev0.1





70V, 6.1mΩ, 51A, N-Channel MOSFET

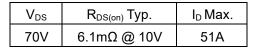
1.Features

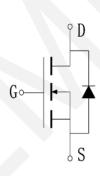
- ◆ Advanced Trench Technology
- ◆ Excellent R_{DS(ON)} and Low Gate Charge
- ◆ Lead Free
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

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- ◆ Load Switch
- PWM Application
- ◆ Power Management







Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Part no. Marking		PCS/Tube	PCS/CTN.	
WX060N07KA	060N07	TO-220	50	5,000	

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	70	V
Gate to Source Voltage	V _{GSS}	±20	V
Drain Current (DC)	I _D	51	А
Drain Current (Pulse), PW≤300μs	I _{DP}	204	А
Total Dissipation	P _D	46.3	W
Avalanche Energy, Single Pulsed	E _{AS}	206	mJ
Junction Temperature	T _j	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5.Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to Ambient	$R_{ hetaJA}$	68	°C/W
Junction to case	R _{eJC}	2.7	°C/W

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

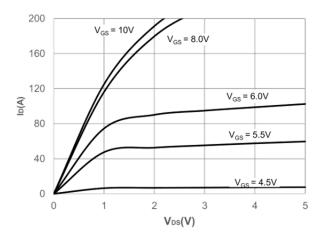
6.Electrical Characteristics at Ta=25°C (Note 3)

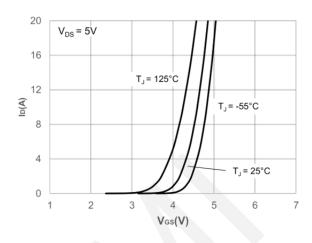
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	70	1	1	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} =68V, V _{GS} = 0V	ı	-	1	μA
Gate to Source Leakage Current	I _{GSS1}	$V_{GS} = \pm 20V, V_{DS} = 0V$,		±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =250μA	2.0	3.0	4.0	V
Static Drain to Source On-State Resistance	R _{DS(on)}	I _D =30A, V _{GS} = 10V	1	6.1	7.9	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	5463	-	pF
Output Capacitance	C _{oss}	V _{DS} =35V,	-	250	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	-	199	-	pF
Turn-on Delay Time	t _{d(on)}		-	20	-	ns
Rise Time	t _r	$V_{DS} = 35V, V_{GS} = 10V,$	-	30	-	ns
Turn-off Delay Time	$t_{d(off)}$	$I_D = 30A, R_{GEN} = 3\Omega$	-	45	-	ns
Fall Time	t _f		-	14	-	ns
	Q_g	V _{DS} =35V,	-	94	-	nC
Total Gate Charge	Q _{gs}	$V_{GS} = 0.00$, $V_{GS} = 0$ to 10V,	-	30	-	nC
	Q_{gd}	I _D =30A	-	24	-	nC
Diode Forward Voltage	V_{FSD}	I _S =30A, V _{GS} = 0	-	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

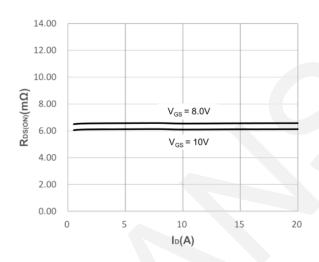


7. Typical electrical and thermal characteristics

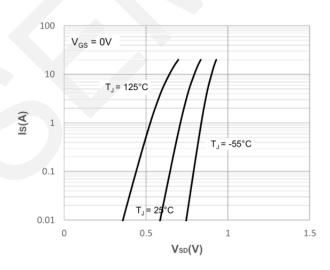




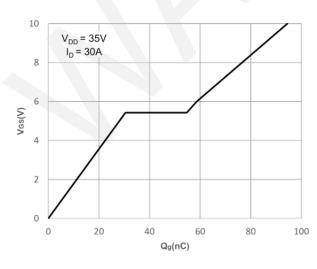
Output Characteristics



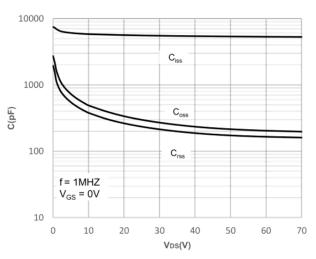
Typical Transfer Characteristics



On-resistance vs. Drain Current



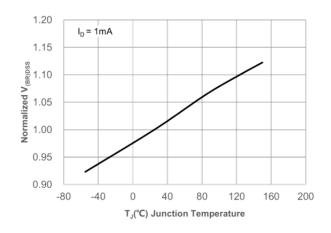
Body Diode Characteristics

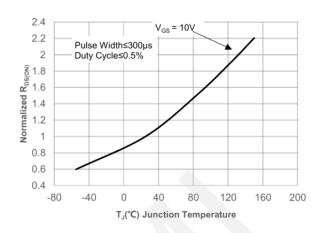


Gate Charge Characteristics

Capacitance Characteristics

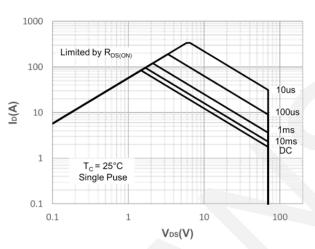






Normalized Breakdown Voltage vs.

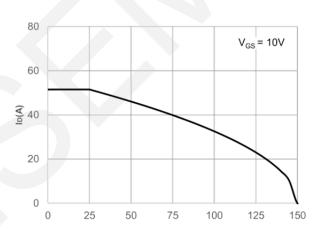
Junction Temperature



Maximum Safe Operating Area

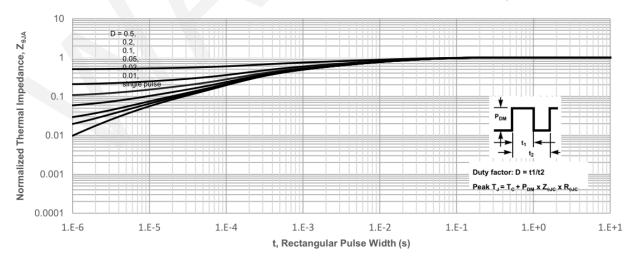
Normalized on Resistance vs.

Junction Temperature



Maximum Continuous Drain Current vs.

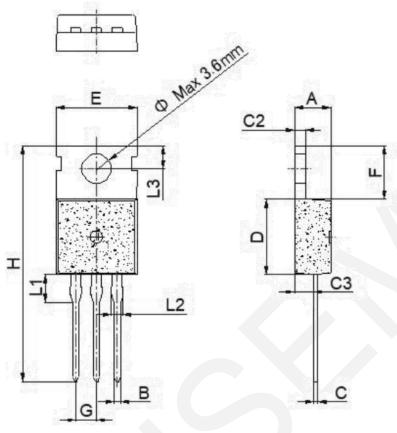
Case Temperature



Normalized Maximum Transient Thermal Impedance



8.Package Dimensions



Ref.			Dime	ensions		
	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	4.40		4.60	0.173		0.181
В	0.70		0.90	0.028		0.035
С	0.45		0.60	0.018		0.024
C2	1.23		1.32	0.048		0.052
C3	2.20		2.60	0.087	~	0.102
D	8.90		9.90	0.350		0.390
Е	9.90		10.3	0.390		0.406
F	6.30		6.90	0.248		0.272
G		2.54			0.1	
Н	28.0		29.8	1.102		1.173
L1		3.39			0.133	0 11 100 11
L2	1.14		1.70	0.045		0.067
L3	2.65		2.95	0.104		0.116
Φ		3.6			0.142	



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